Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/796,021	HORNG ET AL.
Examiner	Art Unit
Tran N. Nguyen	2834

SEARCHED			
Class	Subclass	Date	Examiner
310	156.02 156.04 156,74	4/14/	
	156,74	105	TAD
	156.77		
310	51	V	

INTERFERENCE SEARCHED						
Subclass	Date	Examiner				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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